Search Notes



Application/Control No.	Applicant(s)/Patent under Reexamination
10/624,628	TRAN, LUAN C.
Examiner	Art Unit
Jennifer M Kennedy	2812

	SEVD	CHED	
	JEAR	CHED	
Class	Subclass	Date	Examiner
438	194-196	2/16/2005	JMK
438	217-219	2/16/2005	JMK
438	229-233	2/16/2005	JMK
438	585-587	2/16/2005	JMK
438	551, 592	2/16/2005	JMK
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INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner	

	DATE	EXMR
consulted parent/related cases 10/229336 10/364054 10/367520 10/624627 10/624716	2/16/2005	ЈМК
east text	2/16/2004	JMK
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